## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

## PATENT APPLICATION

Applicants: Dor et al.

4744/04 PDC/MDR/OR

(was 4745 FET/MDR)

Serial No.:

09/905,514

Filed: July 13, 2001

Group Art Unit: 2812

Examiner: Not yet assigned

Title: METHOD, COMPUTER READABLE MEDIUM AND APPARATUS FOR ACCESSING

A DEFECT KNOWLEDGE LIBRARY OF A DEFECT SOURCE IDENTIFICATION

Assistant Commissioner for Patents Washington, D. C. 20231

SIR:

## PRELIMINARY AMENDMENT

Please amend the above-identified patent application as follows:

## IN THE SPECIFICATION

Please replace existing paragraphs [0001] and [0018] with the following paragraphs:

[0001] This application claims benefit of United States provisional patent application serial number 60/240,631, filed October 16, 2000, which is herein incorporated by reference. This application contains subject matter that is related to the subject matter described in US patent application serial numbers 09/905,313, 09/905,609, and 09/905,607, filed simultaneously herewith on July 13, 2001, which are each incorporated herein by reference in their entireties.

[0018] The client computer 110 operates to collect defect, defect source, and defect mitigation data from a semiconductor wafer processing system 116<sub>n</sub>. The system 116<sub>n</sub> is coupled to the subscriber equipment 106. The semiconductor wafer

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